Issue	Classification	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/698,000	FIELD ET AL.	
Examiner	Art Unit	
Kien T. Nguyen	3711	

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	Application/Control No.		Applicant(s)/Patent under Reexamination
Issue Classification			FIELD ET AL.
	Examiner		Art Unit
	Nguyen, Kien T		3711
	ORIGINAL		INTERNATIONAL CLASSIFICATION
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED
472	134	A 6 3 G	31 100 4639
CROSS	CROSS REFERENCE(S)		
CLASS SUBCLASS (	SUBCLASS (ONE SUBCLASS PER BLOCK)		
52 2.11			
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			Total Claims Allowed: 7
(Assistant Examiner)	(Date) Kien Nauven	Junk	O.G. Print Claim(s)
(Legal Instruments Examiner)	(Date) (Primary Examiner)	er) (Date)	

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